



... for a brighter future

Chromium Reactivity and Transport

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U.S. Department
of Energy



A U.S. Department of Energy laboratory
managed by The University of Chicago

Chromium Transport According to Hilpert (*J. Electrochem. Soc.* 143 (1996) 3642)

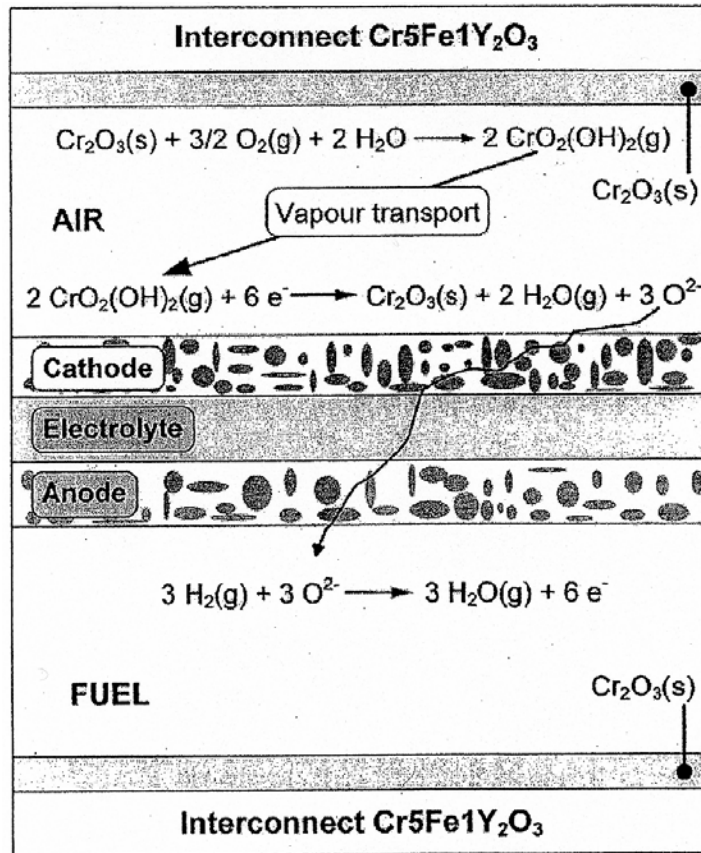


Fig. 6. Cr transport at the cathode side of a SOFC.

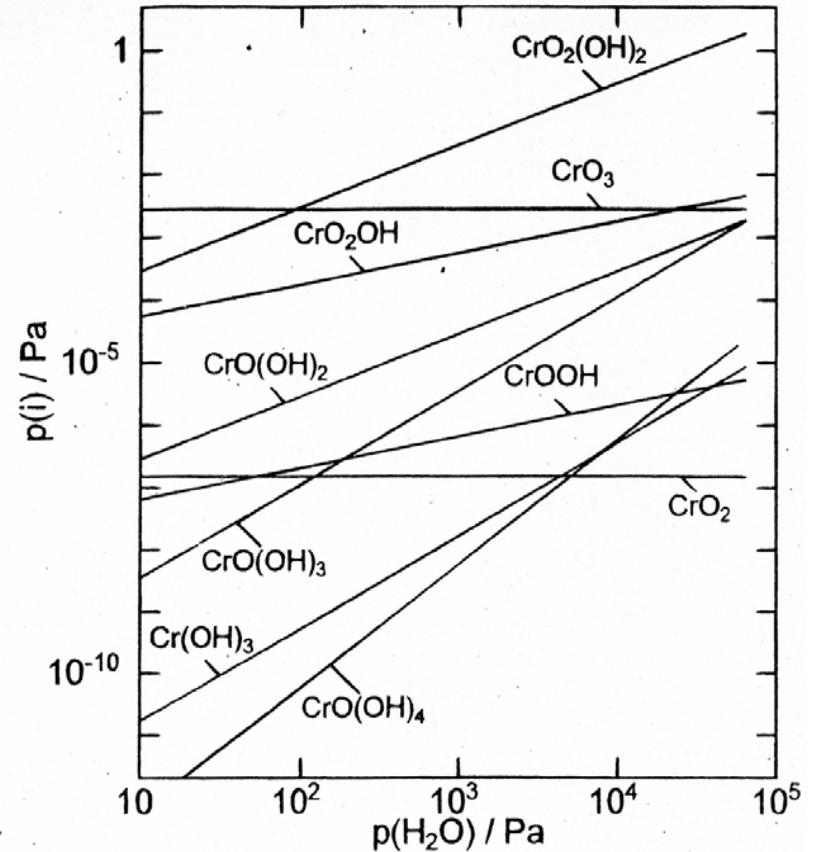
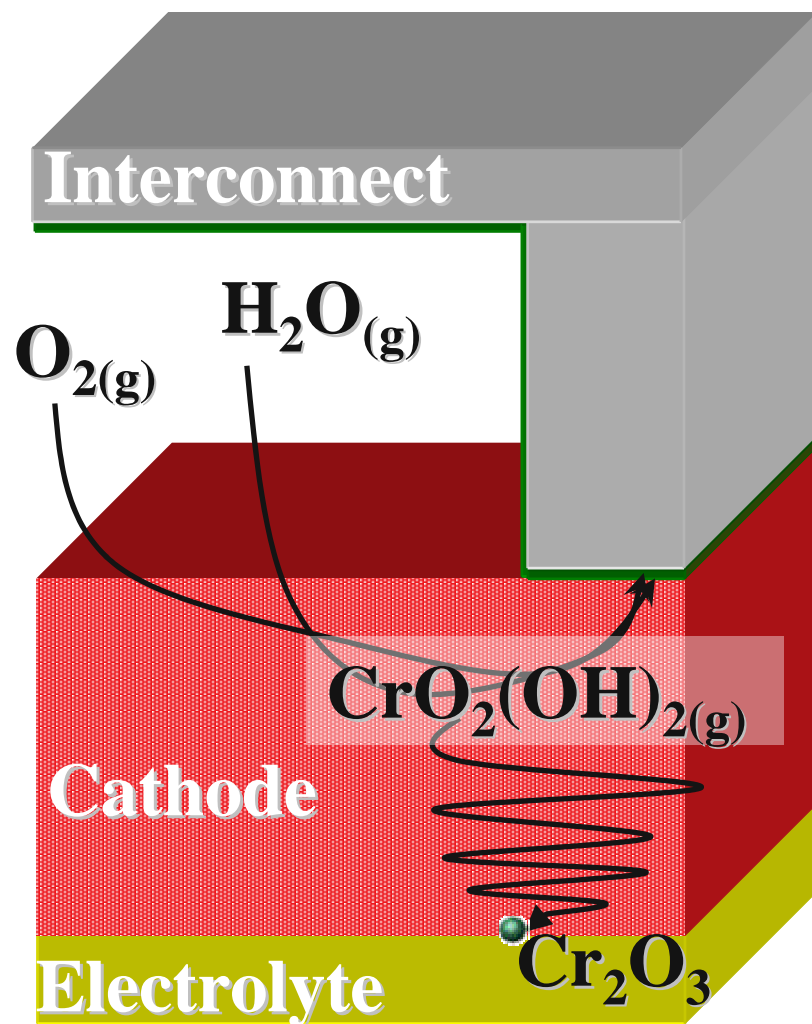
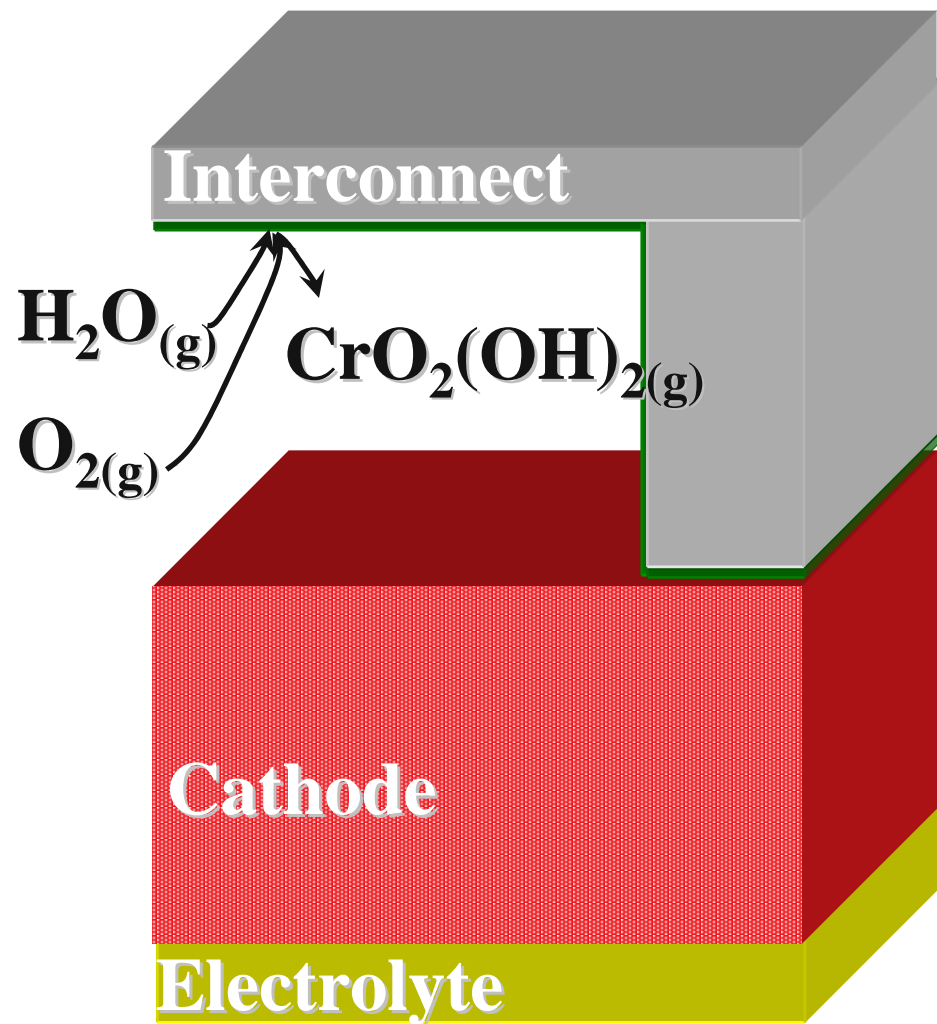
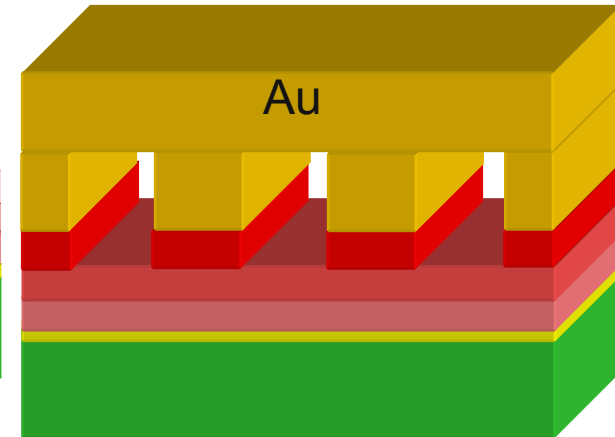
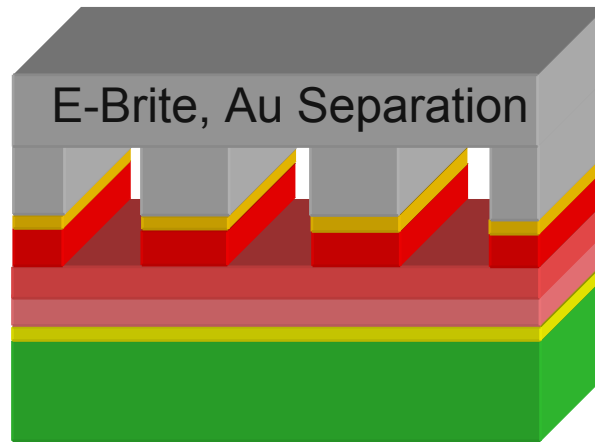
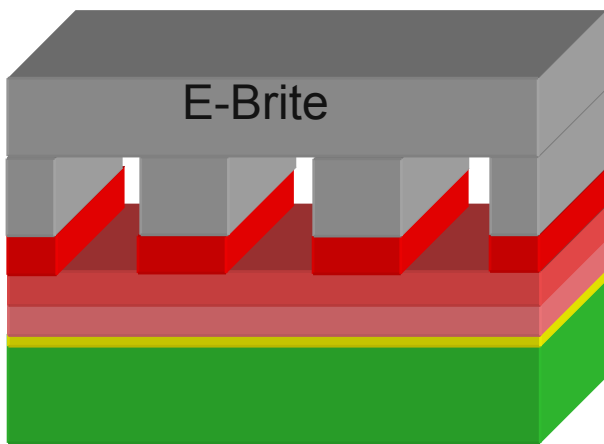


Fig. 3. Partial pressures over $\text{Cr}_2\text{O}_3(\text{s})$ at 1223 K in humid air [$p(\text{O}_2) = 2.13 \times 10^4 \text{ Pa}$] with different H_2O partial pressures.

Flow-channel Hydrodynamics

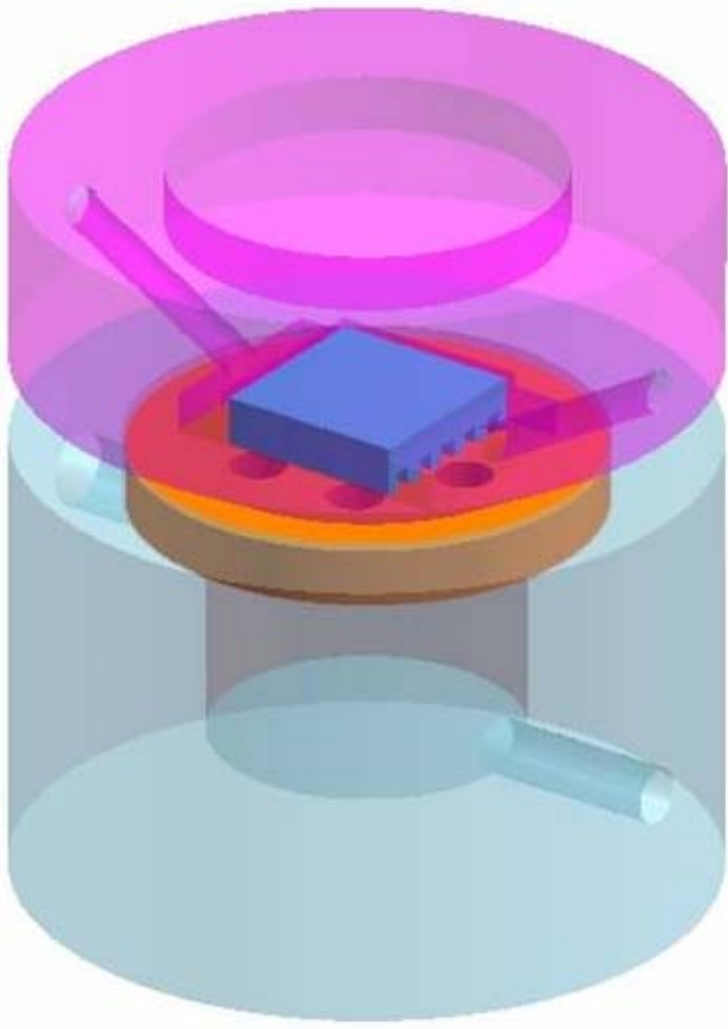


Three Cell Configurations Were Tested



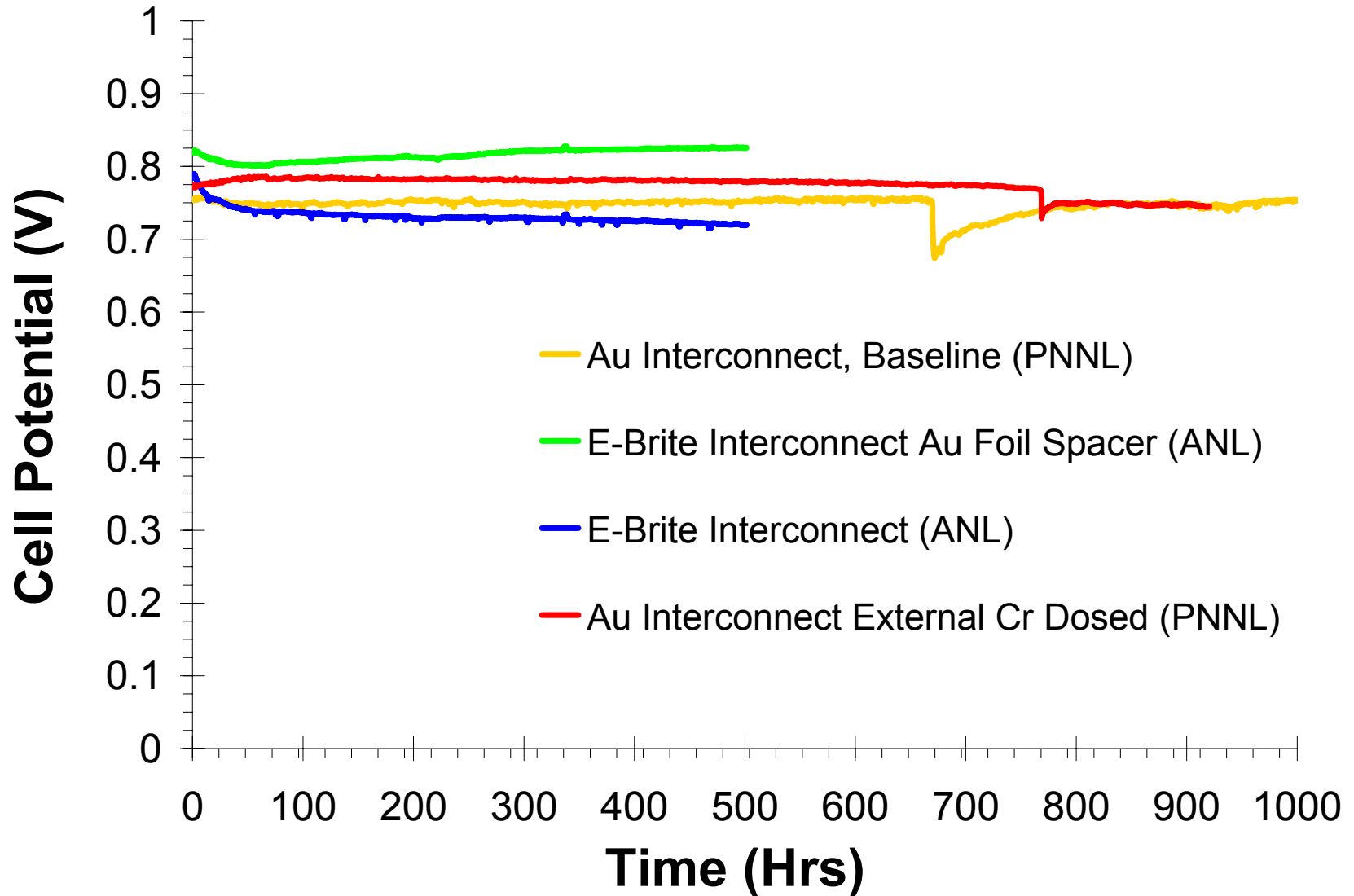
With and without external dosing

Schematic of a Fixture with ribbed Flow-field

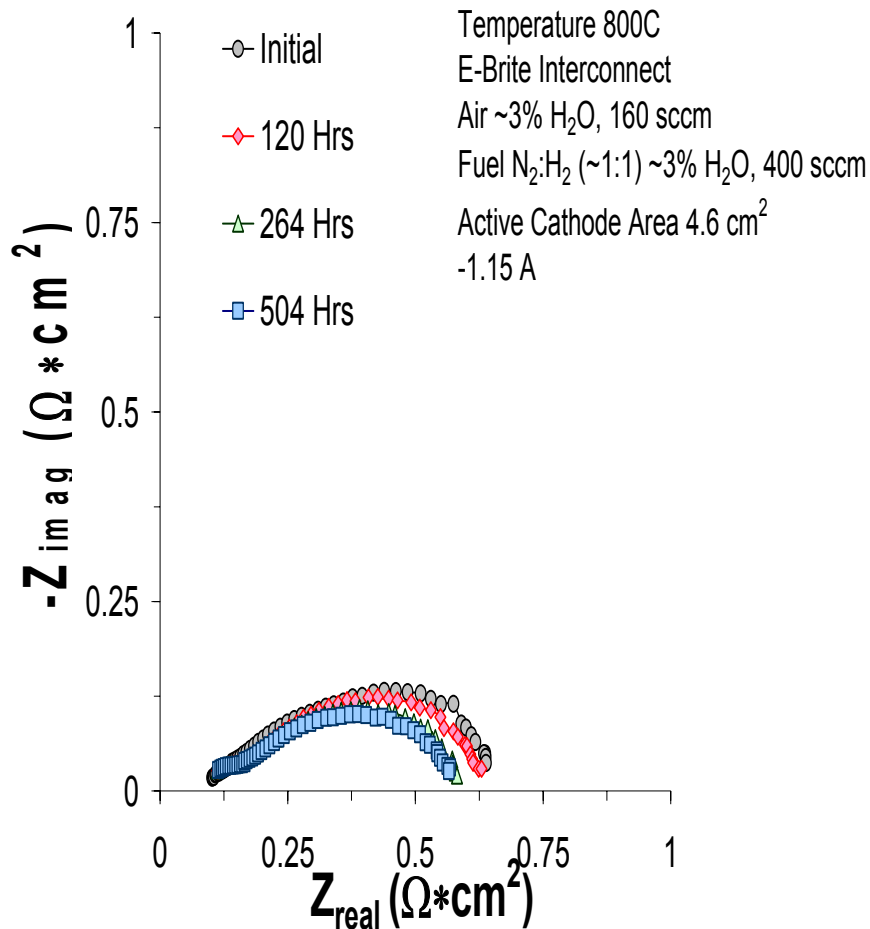


- Metallic Interconnect
 - ANL
 - *E-Brite*
 - *Au Barrier Between E-Brite and Cathode*
 - *Au*
 - PNNL
 - *Au*
 - *Au with External Cr Dosing*
- LSM Contact Paste
- LSM Cathode
- LSM/8YSZ Active Cathode
- 8YSZ Electrolyte
- Ni/8YSZ Anode

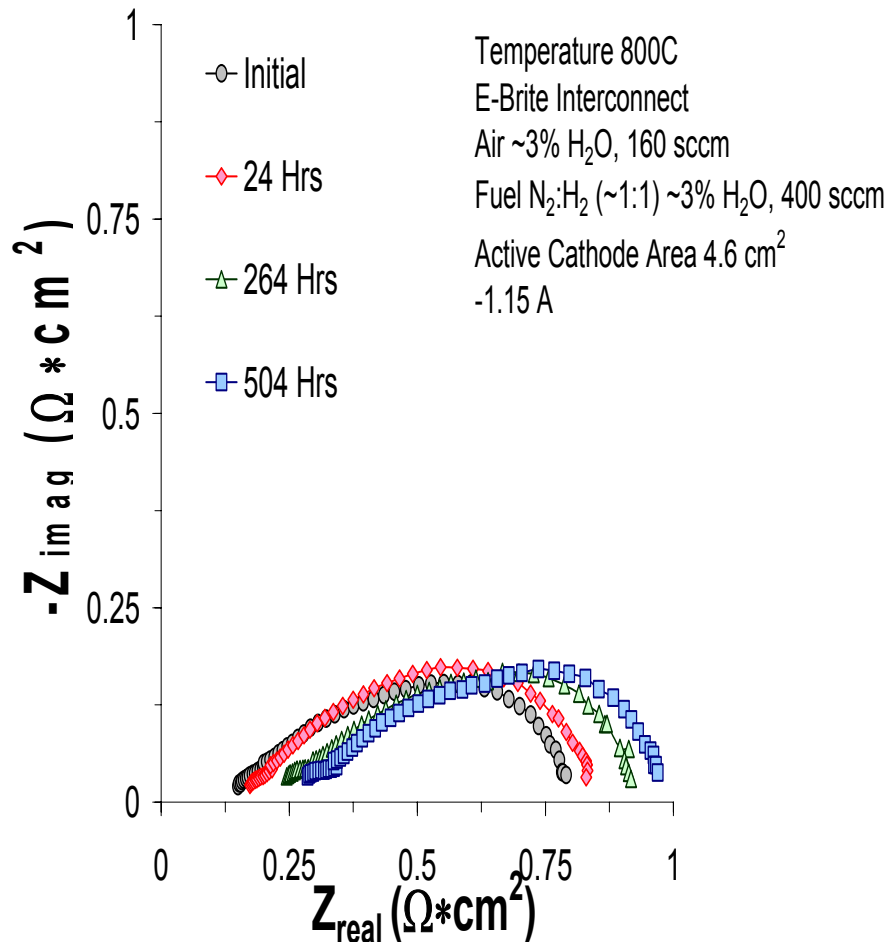
Cell Potentials versus Time



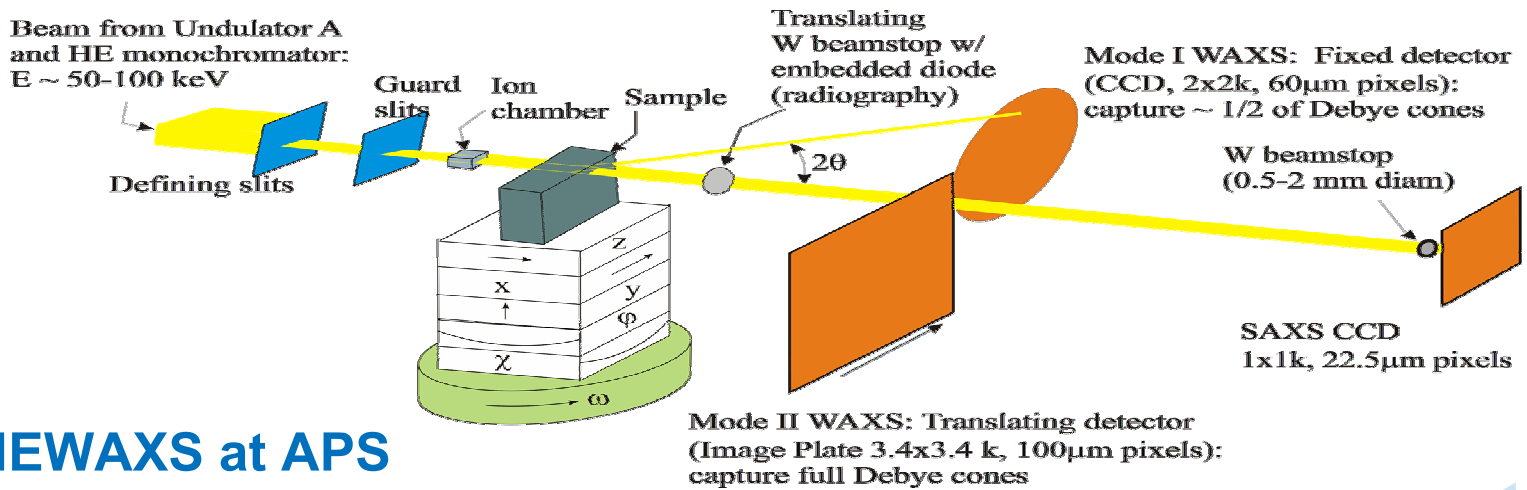
Au Between E-Brite and Cathode



Direct Contact

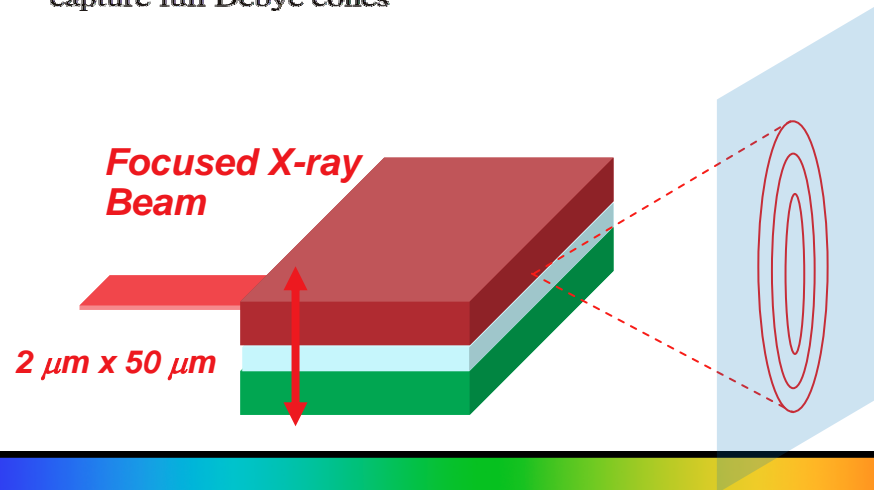
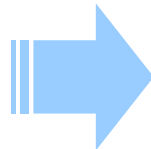


HEWAXS at Argonne APS is a Powerful Tool for Microscopic XRD Investigation

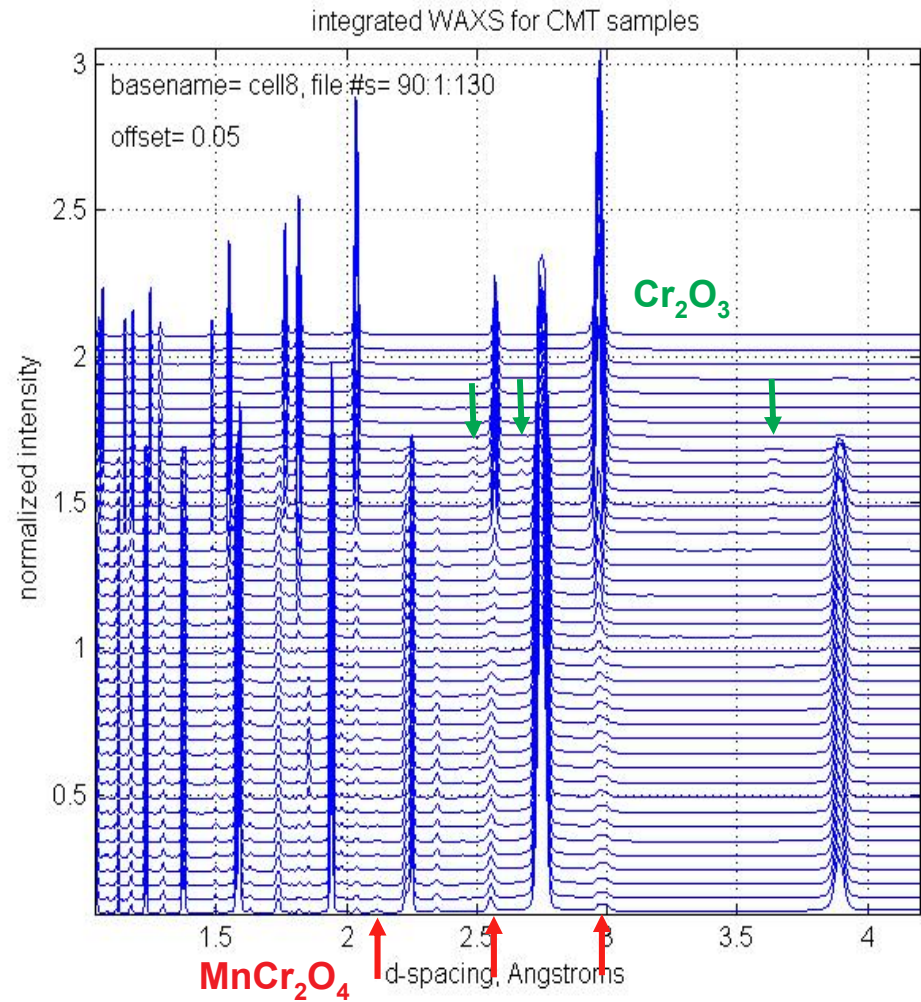
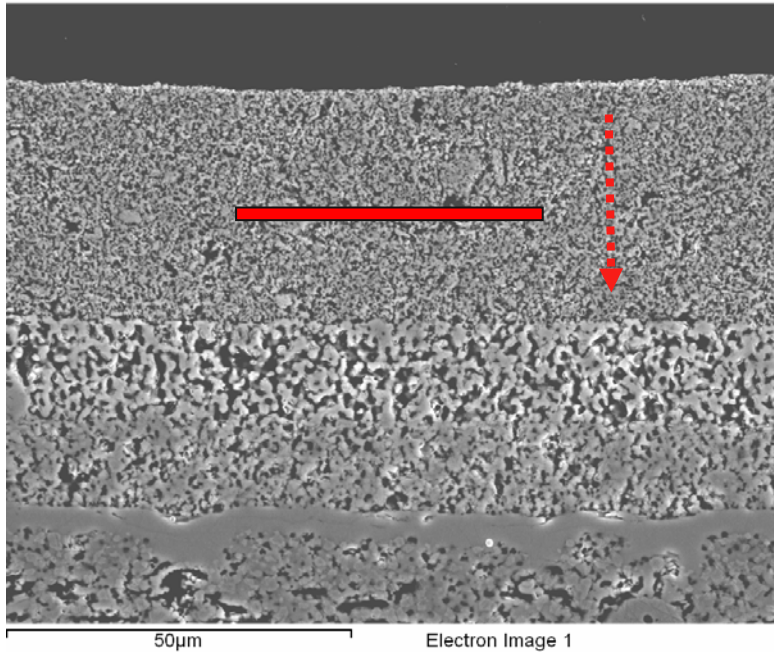


HEWAXS at APS

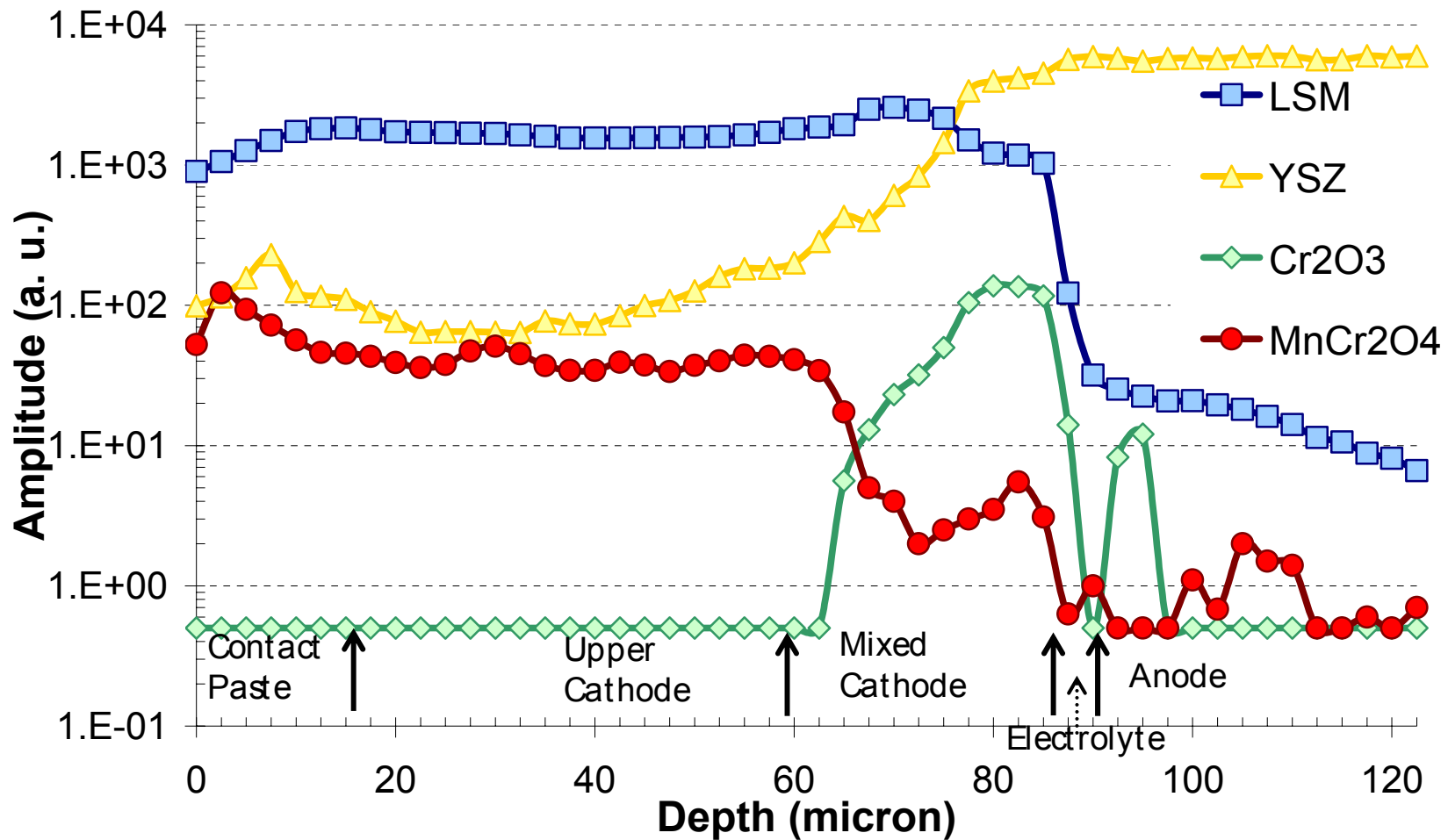
Investigation for Cr poisoned SOFC



Cr₂O₃ and MnCr₂O₄ were unambiguously identified

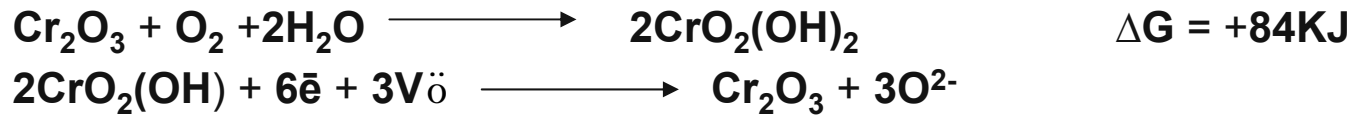


Profiles across Cathode

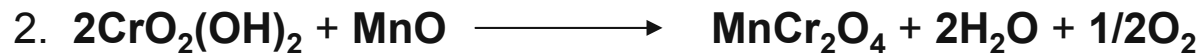
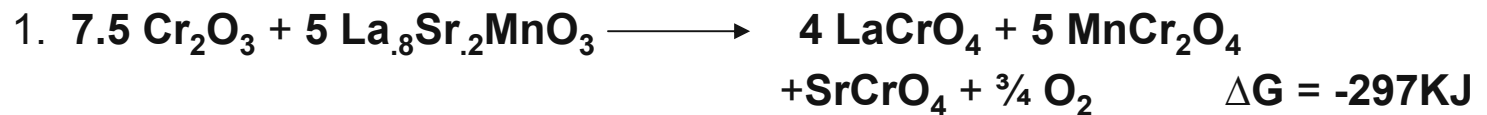


Formation and Transport of Chromium Compounds

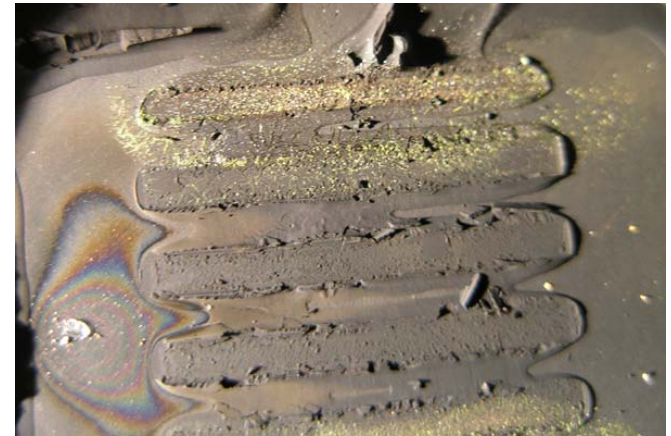
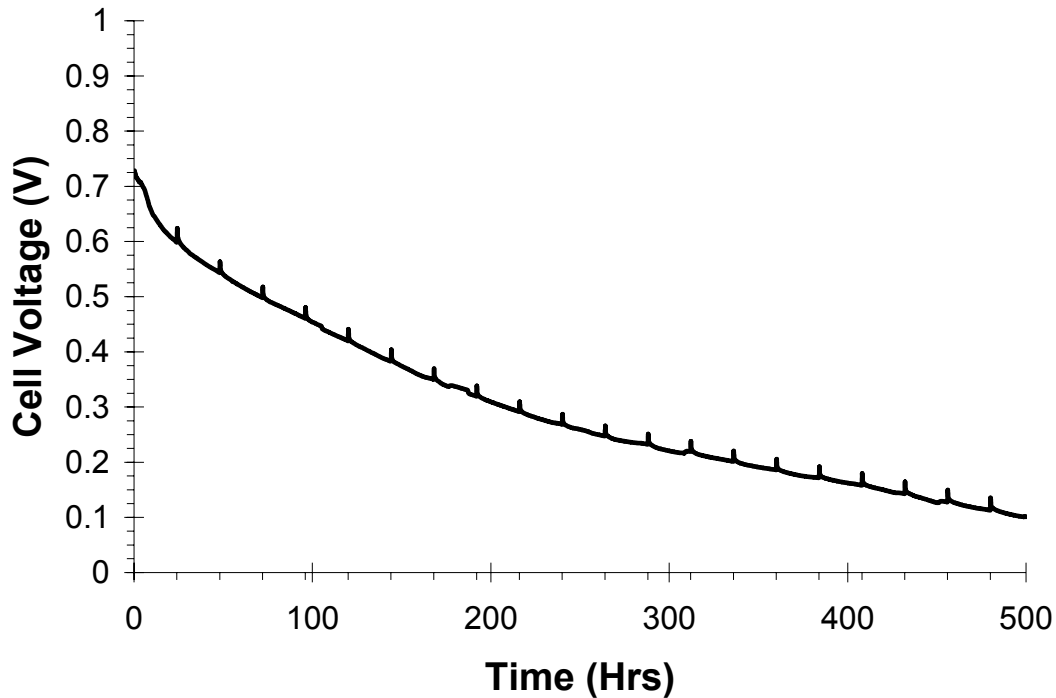
■ Cr₂O₃:



■ MnCr₂O₄:



Incremental Chromium Transport in MACOR fixture



■ $K_2Cr_2O_7$ was identified as a condensate in the exhaust tube

Chromium Mass Balances

Oxyhydroxide formation:

- theoretical: 15 mg
- measured: 0.22 mg

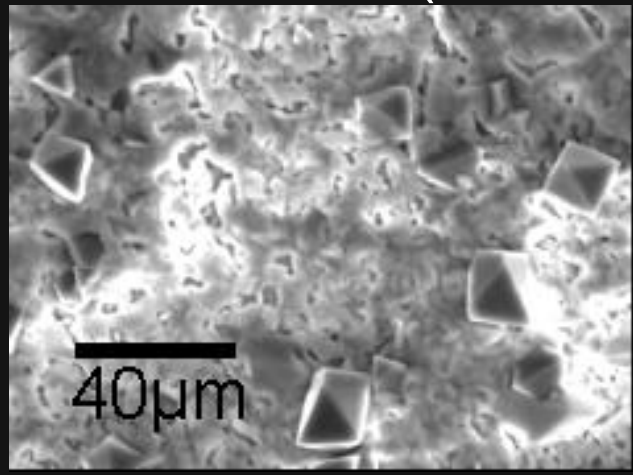
Cr₂O₃ deposits:

- E-Brite with gold foil: not detectable
- E-Brite: 0.12 mg
- E-Brite in Macor: 1.5 mg

Summary

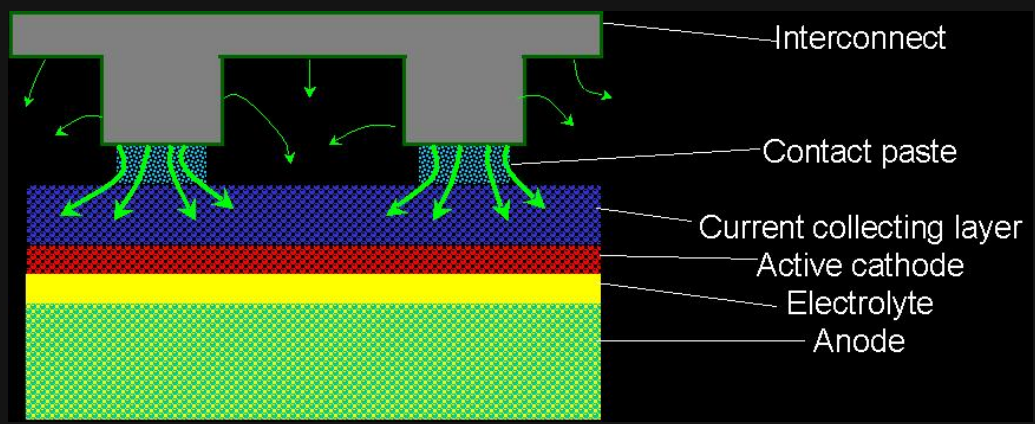
- Hilpert's oxyhydroxide mechanism can account for a cell potential degradation of 5% with E-Brite current collectors
- Spinel forming alloys or spinel coatings will largely prevent the chromium transport
- Alkali and perhaps alkaline earth oxides can dramatically increase it

Cr deposited from vapor on LSM surface (1000°C)

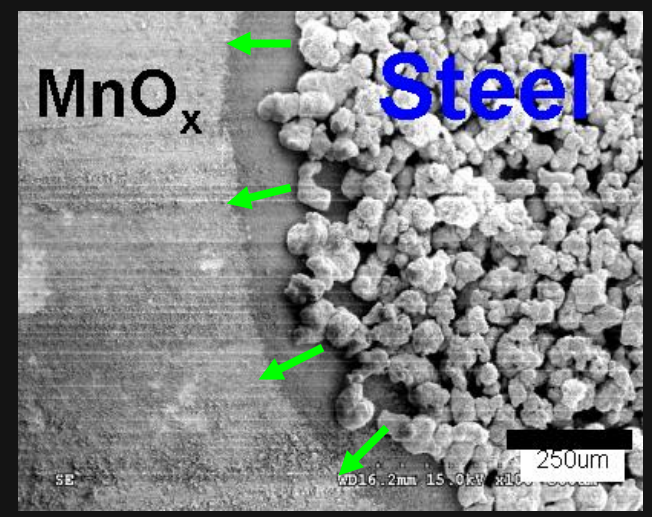


2 transport mechanisms for Cr: vapor and solid state diffusion

Both mechanisms are material and temperature dependent.
Cr transport into the cathode is greatly reduced by lowering the operating temperature to a range suitable for metallic components (650-750°C).
However it does not stop solid state transport through the contact paste. Barrier layers or coatings solve this problem.



Cr diffusion across surface of oxide (800°C)

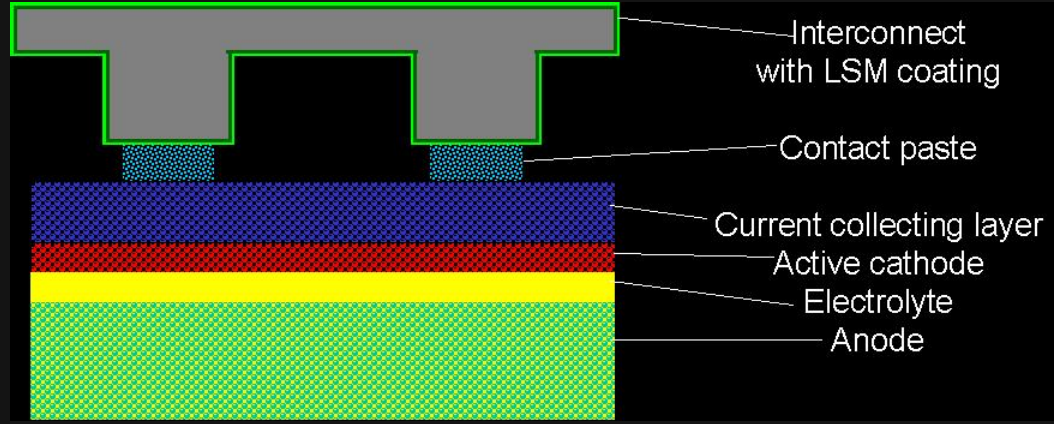


Solutions for Coated Interconnect

Coating decreases Cr vaporization rate by ~100x.

Contact paste can be Ag, LSM, LNF, etc.

Contact paste and/or current collection layer can include Cr getters such as Co to further protect the cathode.



Solutions for Uncoated Interconnect

Choose a contact paste that does not have significant solid state diffusion or vapor deposition (Ag), or a contact paste that reacts with the chromia scale to form an effective barrier.

Accept degradation rate or develop Cr tolerant cathodes.

